R&S®RTE Digital Oscilloscope Specifications









Data Sheet | 06.00

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R&S®RTE-K2 20 R&S®RTE-K3 20 R&S®RTE-K4 22 R&S®RTE-K5 23 R&S®RTE-K6 24 R&S®RTE-K7 25 R&S®RTE-K8 25 R&S®RTE-K9 26 R&S®RTE-K10 26 R&S®RTE-K17 27	R&S®RTE-B19	18
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Definitions

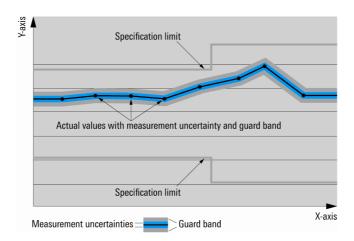
General

Product data applies under the following conditions:

- · Three hours storage at ambient temperature followed by 30 minutes warm-up operation
- Specified environmental conditions met
- · Recommended calibration interval adhered to
- · All internal automatic adjustments performed, if applicable

Specifications with limits

Represent warranted product performance by means of a range of values for the specified parameter. These specifications are marked with limiting symbols such as $\langle , \leq , \rangle > , \geq , \pm$, or descriptions such as maximum, limit of, minimum. Compliance is ensured by testing or is derived from the design. Test limits are narrowed by guard bands to take into account measurement uncertainties, drift and aging, if applicable.



Specifications without limits

Represent warranted product performance for the specified parameter. These specifications are not specially marked and represent values with no or negligible deviations from the given value (e.g. dimensions or resolution of a setting parameter). Compliance is ensured by design.

Typical data (typ.)

Characterizes product performance by means of representative information for the given parameter. When marked with <, > or as a range, it represents the performance met by approximately 80 % of the instruments at production time. Otherwise, it represents the mean value.

Nominal values (nom.)

Characterize product performance by means of a representative value for the given parameter (e.g. nominal impedance). In contrast to typical data, a statistical evaluation does not take place and the parameter is not tested during production.

Measured values (meas.)

Characterize expected product performance by means of measurement results gained from individual samples.

Uncertainties

Represent limits of measurement uncertainty for a given measurand. Uncertainty is defined with a coverage factor of 2 and has been calculated in line with the rules of the Guide to the Expression of Uncertainty in Measurement (GUM), taking into account environmental conditions, aging, wear and tear.

Device settings and GUI parameters are indicated as follows: "parameter: value".

Typical data as well as nominal and measured values are not warranted by Rohde & Schwarz.

Base unit

Vertical system

Input channels	R&S [®] RTE1022	2 channels	
mpat onarmois	R&S®RTE1024	4 channels	
	R&S®RTE1032	2 channels	
	R&S®RTE1034	4 channels	
	R&S®RTE1052	2 channels	
	R&S®RTE1054	4 channels	
	R&S®RTE1102	2 channels	
	R&S®RTE1104	4 channels	
	R&S®RTE1152	2 channels	
	R&S®RTE1154	4 channels	
	R&S®RTE1202	2 channels	
	R&S®RTE1204	4 channels	
Input impedance	TGO TTE 1204	50 Ω ± 1.5 %	
mpat impedance		$1 \text{ M}\Omega \pm 1 \% \parallel 17 \text{ pF} \pm 1 \text{ pF (meas.)}$	
Analog bandwidth (–3 dB)	at 50 Ω input impedance	· · · · · · · · · · · · · · · · · · ·	
. maiog sanaman (o as)	R&S®RTE1022 and R&S®RTE1024	≥ 200 MHz	
	R&S®RTE1032 and R&S®RTE1034	≥ 350 MHz	
	R&S®RTE1052 and R&S®RTE1054	≥ 500 MHz	
	R&S®RTE1102 and R&S®RTE1104	≥ 1 GHz	
	R&S®RTE1152 and R&S®RTE1154	≥ 1.5 GHz	
	R&S®RTE1202 and R&S®RTE1204	≥ 2 GHz	
	at 1 M Ω input impedance	- Z 011Z	
	R&S®RTE1022 and R&S®RTE1024	≥ 200 MHz (meas.)	
	R&S®RTE1032 and R&S®RTE1034	≥ 350 MHz (meas.)	
	R&S®RTE1052, R&S®RTE1054,	≥ 500 MHz (meas.)	
	R&S®RTE1102, R&S®RTE1104,	= 000 III i2 (III000.)	
	R&S®RTE1152, R&S®RTE1154,		
	R&S®RTE1202, and R&S®RTE1204		
Analog bandwidth limits	max. –1.5 dB, min. –4 dB	200 MHz, 20 MHz	
Rise time/fall time	10 % to 90 % at 50 Ω (calculated)		
race amoral amo	R&S®RTE1022 and R&S®RTE1024	< 1.75 ns	
	R&S®RTE1032 and R&S®RTE1034	< 1 ns	
	R&S®RTE1052 and R&S®RTE1054	< 700 ps	
	R&S®RTE1102 and R&S®RTE1104	< 350 ps	
	R&S®RTE1152 and R&S®RTE1154	< 233 ps	
	R&S®RTE1202 and R&S®RTE1204	< 175 ps	
Input VSWR	input frequency ≤ 500 MHz	1.25 (meas.)	
	input frequency > 500 MHz	1.4 (meas.)	
Vertical resolution	mpar nequency essimiz	8 bit,	
		16 bit for high resolution decimation (with	
		reduction of the sampling rate),	
		16 bit for high definition mode (without	
		reduction of the sampling rate, requires	
		the option R&S®RTE-K17)	
Effective number of bits of digitizer	for full-scale sine-wave signal with	> 7.0 bit (meas.)	
2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2	frequency equal to or lower than –3 dB		
	bandwidth		
DC gain accuracy	offset and position set to 0 V, after self-alignment		
-	input sensitivity > 5 mV/div	±1.5 %	
	input sensitivity ≤ 5 mV/div	±2 %	
Input coupling	at 50 Ω	DC and GND	
	at 1 MΩ	DC, AC and GND	
Input sensitivity	at 50 Ω	500 μV/div to 1 V/div	
	at 1 MΩ	500 µV/div to 10 V/div	
Maximum input voltage	at 50 Ω	5 V (RMS)	
	at 1 MΩ	150 V (RMS), 200 V (V _p),	
		derates at 20 dB/decade to 5 V (RMS)	
	II	, ,	
		above 250 kHz	

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Offset range at 50 Ω	input sensitivity		
- -	280 mV/div to 1 V/div ±10 V		
	80 mV/div to ≤ 280 mV/div	±(4.9 V – input sens	sitivity × 5 div)
	500 μV/div to ≤ 80 mV/div	±(1.6 V – input sens	sitivity × 5 div)
Offset range at 1 MΩ	input sensitivity		
	900 mV/div to 10 V/div	±(129.5 V - input se	ensitivity × 5 div)
	80 mV/div to ≤ 900 mV/div	±(12.4 V - input ser	nsitivity × 5 div)
	500 μV/div to ≤ 80 mV/div	±(1.15 V – input sei	
Offset accuracy		±(0.5 % × net offse	et + 1 mV + 0.15 div
		input sensitivity)	
		(net offset =	
		offset – position × ii	
DC measurement accuracy	after adequate suppression of	±(DC gain accuracy	
	measurement noise using high-resolution	reading - net offset	
	sampling mode or waveform averaging or	+ offset accuracy)	
	a combination of both		
Channel-to-channel isolation	input frequency ≤ 1 GHz	> 50 dB	
each channel at same input sensitivity)	input frequency > 1 GHz	> 40 dB	
RMS noise floor at 50 Ω (typ.)	input sensitivity	R&S®RTE1022,	R&S®RTE1032,
		R&S®RTE1024	R&S®RTE1034
	500 μV/div	0.04 mV	0.06 mV
	1 mV/div	0.04 mV	0.06 mV
	2 mV/div	0.07 mV	0.08 mV
	5 mV/div	0.13 mV	0.15 mV
	10 mV/div	0.20 mV	0.24 mV
	20 mV/div	0.30 mV	0.40 mV
	50 mV/div	0.75 mV	0.99 mV
	100 mV/div	1.46 mV	1.97 mV
	200 mV/div	2.81 mV	3.77 mV
	500 mV/div	7.84 mV	10.4 mV
	1 V/div	13.4 mV	17.9 mV
	input sensitivity	R&S®RTE1052,	R&S®RTE1102,
		R&S®RTE1054	R&S®RTE1104
	500 μV/div	0.08 mV	0.10 mV
	1 mV/div	0.08 mV	0.10 mV
	2 mV/div	0.10 mV	0.13 mV
	5 mV/div	0.18 mV	0.24 mV
	10 mV/div	0.27 mV	0.34 mV
	20 mV/div	0.45 mV	0.55 mV
	50 mV/div	1.13 mV	1.39 mV
	100 mV/div	2.23 mV	2.76 mV
	200 mV/div	4.31 mV	5.34 mV
	500 mV/div	11.9 mV	14.5 mV
	1 V/div	20.6 mV	25.4 mV
	input sensitivity	R&S®RTE1152, R&S®RTE1154	R&S®RTE1202, R&S®RTE1204
	500 μV/div	0.13 mV	0.15 mV
	1 mV/div	0.13 mV	0.15 mV
	2 mV/div	0.16 mV	0.18 mV
	5 mV/div	0.27 mV	0.30 mV
	10 mV/div	0.38 mV	0.42 mV
	20 mV/div	0.60 mV	0.66 mV
	50 mV/div	1.51 mV	1.66 mV
	100 mV/div	3.01 mV	3.25 mV
	200 mV/div	5.81 mV	6.26 mV
	500 mV/div	15.8 mV	17.4 mV
	1 V/div	27.1 mV	29.8 mV

Horizontal system

Timebase range		selectable between 50 ps/div and 5000 s/div.
		time per div settable to any value within range
Channel deskew		±100 ns
Reference position		0 % to 100 % of measurement display
		area
Trigger offset range	max.	+(memory depth/current sampling rate)
	min.	-10 000 s
Modes		normal, roll
Channel-to-channel skew		< 100 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23 °C	±2 ppm
	during calibration interval	±4 ppm
Delta time accuracy	corresponds to time error between two	±(K/realtime sampling rate +
	edges on same acquisition and channel;	timebase accuracy × reading) (peak)
	signal amplitude greater than 5 divisions,	(meas.)
	measurement threshold set to 50 %,	where
	vertical gain 10 mV/div or greater;	K = 0.2 (R&S [®] RTE1022, R&S [®] RTE1024)
	rise time lower than four sample periods;	K = 0.24 (R&S®RTE1032, R&S®RTE1034)
	waveform acquired in realtime mode	K = 0.27 (R&S®RTE1052, R&S®RTE1054)
	·	K = 0.34 (R&S®RTE1102, R&S®RTE1104)
		K = 0.38 (R&S®RTE1152, R&S®RTE1154)
		K = 0.42 (R&S®RTE1202, R&S®RTE1204)

Acquisition system

Realtime sampling rate		max. 5 Gsample/s on each channel	
Realtime waveform acquisition rate	max.	> 1 000 000 waveforms/s	
Memory depth	standard		
	R&S®RTE1022, R&S®RTE1032,	10 Msample on 2 channels,	
	R&S®RTE1052, R&S®RTE1102,	20 Msample on 1 channel	
	R&S®RTE1152, R&S®RTE1202		
	R&S®RTE1024, R&S®RTE1034,	10 Msample on 4 channels,	
	R&S®RTE1054, R&S®RTE1104,	20 Msample on 2 channels,	
	R&S®RTE1154, R&S®RTE1204	40 Msample on 1 channel	
	R&S®RTE-B101 option		
	R&S®RTE1022, R&S®RTE1032,	20 Msample on 2 channels,	
	R&S®RTE1052, R&S®RTE1102,	40 Msample on 1 channel	
	R&S®RTE1152, R&S®RTE1202	·	
	R&S®RTE1024, R&S®RTE1034,	20 Msample on 4 channels,	
	R&S®RTE1054, R&S®RTE1104,	40 Msample on 2 channels,	
	R&S®RTE1154, R&S®RTE1204	80 Msample on 1 channel	
	R&S®RTE-B102 option		
	R&S®RTE1022, R&S®RTE1032,	50 Msample on 2 channels,	
	R&S®RTE1052, R&S®RTE1102,	100 Msample on 1 channel	
	R&S®RTE1152, R&S®RTE1202	·	
	R&S®RTE1024, R&S®RTE1034,	50 Msample on 4 channels,	
	R&S®RTE1054, R&S®RTE1104,	100 Msample on 2 channels,	
	R&S®RTE1154, R&S®RTE1204	200 Msample on 1 channel	
Decimation modes		selection valid for all channels	
	sample	first sample in decimation interval	
	peak detect	largest and smallest sample in decimation interval	
	high resolution	average value of samples in decimation interval	
	root mean square	root of squared average of samples in decimation interval	

Waveform arithmetic		selection valid for all channels
	off	no arithmetic
	envelope	envelope of acquired waveforms
	average	average of acquired waveforms,
		max. average depth depends on
		decimation mode 1
	sample	max. 16 777 215
	high resolution	max. 65 535
	root mean square	max. 255
	reset condition	no reset (standard), manual reset
Sampling modes	realtime mode	max. sampling rate set by digitizer
	interpolated time	enhancement of sampling resolution by
		interpolation; max. equivalent sampling
		rate is 2 Tsample/s
Interpolation modes		linear, sin(x)/x, sample&hold
Ultra segmented mode		continuous recording of waveforms in
		acquisition memory without interruption
		due to visualization; blind time between
		consecutive acquisitions less than 400 ns

Trigger system

Sources	R&S®RTE1022, R&S®RTE1032,	channel 1, channel 2
	R&S®RTE1052, R&S®RTE1102,	
	R&S®RTE1152, R&S®RTE1202	
	R&S®RTE1024, R&S®RTE1034,	channel 1, channel 2, channel 3, channel 4
	R&S®RTE1054, R&S®RTE1104,	
	R&S®RTE1154, R&S®RTE1204	
Sensitivity	trigger hysteresis mode	auto (standard) or manual
	range	0 V to 5 div × input sensitivity
Trigger jitter	full-scale sine wave of frequency set to	< 1 ps (RMS) (meas.)
	-3 dB bandwidth	
Coupling mode	standard	same as selected channel
	lowpass filter	cutoff frequency selectable from 50 kHz to
		50 % of analog bandwidth
Sweep mode		auto, normal, single, n single
Event rate	max.	one event for every 800 ps time interval
Trigger level	range	±5 div from center of screen
Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Main trigger modes			
Edge	triggers on specified slope (pos	triggers on specified slope (positive, negative or either) and level	
Glitch	triggers on glitches of positive, specified width	negative or either polarity that are shorter or longer than	
	glitch width	200 ps to 1000 s	
Width	triggers on positive or negative inside or outside the interval	pulse of specified width; width can be shorter, longer,	
	pulse width	200 ps to 1000 s	
Runt	fails to cross a second threshold	triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before crossing the first one again; runt pulse width can be arbitrary, shorter, longer, inside or outside the interval	
Window	triggers when signal enters or e	runt pulse width 200 ps to 1000 s triggers when signal enters or exits a specified voltage range; triggers also when signal stays inside or outside the voltage range for a specified period of time	
Timeout	triggers when signal stays high, timeout	triggers when signal stays high, low or unchanged for a specified period of time	
Interval		triggers when time between two consecutive edges of same slope (positive or negative) is shorter, longer, inside or outside a specified range interval time 200 ps to 1000 s	

¹ Waveform averaging is not compatible with peak detect decimation.

Slew rate		y a signal edge to toggle between user-defined upper er, longer, inside or outside the interval; edge slope		
	may be positive, negative or eith	er		
	toggle time	200 ps to 1000 s		
Data2clock	triggers on setup time and hold to	me violations between clock and data present on any		
	two input channels; monitored tir	ne interval may be specified by the user in the range		
	from -100 ns to 100 ns around a	clock edge and must be at least 200 ps wide		
Pattern triggers when a logical combination (AND, NAND, OF		on (AND, NAND, OR, NOR) of the input channels		
	stays true for a period of time she	orter, longer, inside or outside a specified range		
State	triggers when a logical combinati	on (AND, NAND, OR, NOR) of the input channels		
	stays true at a slope (positive, ne	stays true at a slope (positive, negative or either) in one selected channel		
Serial pattern	triggers on serial data pattern up	to 128 bit clocked by one input channel; pattern bits		
	may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative or either			
	max. data rate	< 1.25 Gbps		
TV/video	triggers on baseband analog pro	gressive and interlaced video signals including NTSC,		
	PAL, PAL-M, SECAM, EDTV and HDTV broadcast standards as well as custom bi-level			
	and tri-level sync video standard	8		
	trigger modes	all fields, odd fields, even fields, all lines,		
		line number		
Line	triggers with the frequency of the	triggers with the frequency of the AC power line voltage		

Advanced trigger modes			
Sequence trigger (A/B trigger)	triggers on B event after occurrence of A event; delay condition after A event specified either as time interval or number of B events		
	A event	any trigger mode	
	B event	edge	
Serial bus trigger	optional	I ² C, SPI, UART/RS-232, LIN, CAN, FlexRay™, I ² S, MIL-STD-1553, ARINC 429, CAN FD, SENT, Manchester, NRZ, MDIO and USB 1.0/1.1/2.0/HSIC with dedicated software options	
External trigger input	input impedance	$50 \Omega \pm 1.5 \%$ (meas.), 1 MΩ ± 1 % 14 pF (meas.)	
	max. input voltage at 50 Ω	5 V (RMS)	
	max. input voltage at 1 M Ω	30 V (RMS) derates at 20 dB/decade to 5 V (RMS) above 5 MHz	
	trigger level range	±5 V	
	sensitivity, for input frequency ≤ 500 MHz	300 mV (V _{pp})	
	input coupling	AC, DC (50 Ω and 1 MΩ), GND, HF reject (attenuates > 50 kHz), LF reject (attenuates < 50 kHz)	
	trigger modes	edge (rise or fall)	
Trigger out	functionality	a pulse is generated for every acquisition trigger event	
	output voltage	0 V to 5 V at high impedance; 0 V to 2.5 V at 50 Ω	
	pulse width	selectable between 50 ns and 60 ms	
	pulse polarity	low active or high active	
	output delay	depends on trigger settings	
	jitter	±600 ps (meas.)	

Waveform measurements

General features	measurements up to 8 measurements		
	gate	delimits the display region evaluated for automatic measurements	
	reference levels	user-configurable vertical levels define support structures for automatic measurements	
	statistics	displays maximum, minimum, mean, standard deviation, RMS and measurement count for each automatic measurement	
	track	measurement results displayed as continuous trace that is time-correlated to the measurement source; requires R&S®RTO-K31 option	
	long-term analysis	history of selected measurements as trace against count index	
	histogram	available for each measurement independently	
Measurement category	amplitude and time	amplitude, high, low, maximum, minimum, peak-to-peak, mean, RMS, sigma, positive overshoot, area, rise time, fall time, positive width, negative width, period, frequency, positive duty cycle, negative duty cycle, delay, phase, burst width, pulse count, edge count, positive switching, negative switching, cycle area, cycle mean, cycle RMS, cycle sigma, setup time, hold time, setup/hold ratio, pulse train, delay to trigger, DC voltmeter (requires Rohde & Schwarz active probe with R&S®ProbeMeter functionality)	
	eye diagram	extinction ratio (%, dB), eye height, eye width, eye top, eye base, Q factor, noise RMS, S/N ratio, duty cycle distortion, eye rise time, eye fall time, eye bit rate, eye amplitude, jitter (peak-to-peak, 6-sigma, RMS)	
	spectrum	channel power, bandwidth, occupied bandwidth, total harmonic distortion, harmonic search	
Cursors	setup	up to 2 cursor sets on screen, each set consisting of two horizontal and two vertical cursors	
	target	acquired waveforms (input channels), math waveforms, reference waveforms, XY diagrams	
	operating mode	vertical measurements, horizontal measurements or both; vertical cursors either set manually or locked to waveform	
Histogram	source	acquired waveform (input channels), math waveform, reference waveform	
	mode	vertical (for timing statistics), horizontal (for amplitude statistics)	
	automatic measurements	waveform count, waveform samples, histogram samples, histogram peak, peak value, upper peak, lower peak, maximum, minimum, median, range, mean, sigma, mean ± 1, 2 and 3 sigma, marker ± probability	

Quick measurements	function	fast overview of user-configurable measurements from one channel
	number of measurements	up to 8 simultaneously
	measurements	amplitude, high, low, maximum, minimum, peak-to-peak, mean, RMS, sigma, overshoot, area, rise time, fall time, positive width, negative width, period, frequency, duty cycle, burst width, pulse count, edge count, positive switching, negative switching, cycle area, cycle mean, cycle RMS, cycle sigma, pulse train

Mask testing

Test definition	number of masks	up to 8 simultaneously
	source	acquired waveforms (input channels),
		math waveforms, reference waveforms,
		XY graphs
	fail condition	sample hit or waveform hit
	fail tolerance	minimum number of fail events for test fail
		in range from 0 to 4 000 000 000
	action on error	acquisition stop, beep, print and save
		waveform, trigger out
	save/load to file	test and mask settings (.xml format)
Mask definition with segments	number of independent segments	up to 8
	segment definition	array of points and connecting rule (upper, lower, inner) define segment region
	segment input	point and click on touchscreen, editable list
Mask definition with tolerance tube	input signal	acquired waveform
	definition of tolerance tube	horizontal width, vertical width, vertical
		stretch, vertical position
Result statistics	category	completed acquisitions, remaining
		acquisitions, state, sample hits, mask hits,
		fail rate, test result (pass or fail)
Visualization options	waveform style	vectors, dots
	violation highlighting	hits (on/off), highlight persistence
		(50 ms to 50 s or infinite), waveform color (default: red)
	mask colors	configurable colors for mask without violation (default: translucent gray), mask with violation (default: translucent red),
		mask with contact (default: translucent pale red)

Waveform math

General features	number of math waveforms	up to 4
	number of reference waveforms	up to 4
	waveform arithmetic	user-selectable average or envelope of
		consecutive waveforms
Algebraic expressions	user may define complex mathematic	al expressions involving waveforms and
	measurement results	
	math functions	add, subtract, multiply, divide, absolute
		value, square, square root, integrate,
		differentiate, log ₁₀ , log _e , log ₂ , rescale, sin,
		cos, tan, arcsin, arccos, arctan, sinh, cosh,
		tanh, autocorrelation, crosscorrelation
	logical operators	not, and, nand, or, nor, xor, nxor
	relational operators	Boolean result of =, \neq , >, <, \leq , \geq
	frequency domain	spectral magnitude and phase, real and
		imaginary spectra, group delay
	digital filter	lowpass, highpass
Optimized math	operators	add, subtract, multiply, absolute value,
		differentiate, log ₁₀ , log _e , log ₂ , rescale, FIR,
		FFT magnitude
Spectrum analysis	FFT magnitude spectrum	
	setup parameters	center frequency, frequency span, frame
		overlap, frame window (rectangular,
		Hamming, Hann, Blackman, Gaussian,
		Flattop, Kaiser Bessel), user-selectable
		spectrum averaging and envelope

Search and mark function

General description	scans acquired waveforms for occurrence of a user-defined set of events and highlights			
	each occurrence	each occurrence		
Basic setup	source	acquired waveforms (input channels), math waveforms, reference waveforms		
	search panels	up to 4, where each panel may manage multiple event searches		
	search mode	manually triggered or continuous		
	search conditions			
	supported events	edge, glitch, width, runt, window, timeout, interval, slew rate, data2clock, state, pattern		
	event configuration	identical to corresponding trigger event		
	event selection	single or multiple events on same source		
Search scope	mode	current waveform, gated time interval		
Result visualization	table			
	sort mode	horizontal position or vertical value		
	max. result count	specifies max. table size		
	zoom window	centered on highlighted event		

Display characteristics

Diagram types	Yt, XY, spectrum, long-term measurement	
Display interface configuration	display area can be split up into separate diagram areas by dragging and dropping signal icons;	
	each diagram area can hold any number of signals;	
	diagram areas may be stacked on top of each other and later accessed via the dynamic tab menu	
Signal bar	accommodates timebase settings, trigger settings and signal icons;	
	signal bar may be docked to left or right side of display area or hidden	
Signal icon	each active waveform is represented by a separate signal icon on the signal bar; the	
	signal icon displays the individual vertical and acquisition settings; a waveform can be	
	minimized to its signal icon so that it appears as a realtime preview in miniature form;	
	dialog boxes and measurement results may also be minimized to a signal icon	
Axis label	X-axis ticks and Y-axis ticks labeled with tick value and physical unit	
Diagram label	diagrams may be individually labeled with a descriptive user-defined name	
Diagram layout	grid, crosshair, axis labels and diagram label may be switched on and off separately	
Persistence	50 ms to 50 s, or infinite	
Zoom	user-defined zoom window provides vertical and horizontal zoom;	
	each diagram area supports multiple zoom windows;	
	touchscreen interface simplifies resize and drag operations on zoom window	
Signal colors	predefined or user-defined color tables for persistence display	

Input and output

Front		
Channel inputs		BNC-compatible, for details see Vertical system
	probe interface	auto-detection of passive probes, Rohde & Schwarz active probe interface
External trigger input		BNC-compatible, for details see Trigger system
Probe compensation output	signal shape	rectangle, $V_{low} = 0 \text{ V}$, $V_{high} = 1 \text{ V}$ amplitude 1 V (V_{pp}) ± 5 %
	frequency	1 kHz ± 1 %
	impedance	50 Ω (nom.)
Ground jack		connected to ground
USB interface		2 ports, type A plug, version 2.0

Rear		
Trigger out		SMA,
		for details see Trigger system
USB interface		2 ports, type A plug, version 3.0
LAN interface		RJ-45 connector,
		supports 10/100/1000BASE-T
External monitor interface		DVI-D connector,
		output of scope display or extended
		desktop display
Reference input/output	connector	BNC female,
		software switch for selection of
		input/output
	input	
	impedance	50 Ω (nom.)
	input frequency	10 MHz
	required level	\geq 0 dBm into 50 Ω
	output	
	impedance	50 Ω (nom.)
	output frequency	10 MHz (nom.)
	level	> 7 dBm
GPIB interface		see R&S®RTE-B10 option
Security slot		for standard Kensington style lock

General data

Display	type	10.4" LC TFT color display with
		touchscreen
	resolution	1024 × 768 pixel (XGA)

Temperature		
Temperature loading	operating temperature range	0 °C to +45 °C
_	storage temperature range	-40 °C to +70 °C
Climatic loading		+25° C/+40 °C at 85 % rel. humidity cyclic,
-		in line with IEC 60068-2-30

Altitude	
Operating	up to 3000 m above sea level
Nonoperating	up to 4600 m above sea level

Mechanical resistance		
Vibration	sinusoidal	5 Hz to 150 Hz, 1.8 g at 55 Hz, 0.5 g from 55 Hz to 150 Hz, in line with EN 60068-2-6 5 Hz to 55 Hz, in line with MIL-PRF-28800F section 4.5.5.3.2 class 3
	random	10 Hz to 300 Hz, acceleration 1.2 g (RMS), in line with EN 60068-2-64 5 Hz to 500 Hz, acceleration 2.058 g (RMS), in line with MIL-PRF-28800F section 4.5.5.3.1 class 3
Shock		40 g shock spectrum, in line with MIL-STD-810E, method no. 516.4, procedure I 30 g functional shock, halfsine, duration 11 ms, in line with MIL-PRF-28800F section 4.5.5.4.1

EMC		
RF emission	in line with EN 55011 class A, operation in residential, commercial and business areas or in small-size companies is not covered; therefore the instrument may not be operated in residential, commercial and business areas or in small-size companies unless additional measures are taken to ensure that EN 55011 class B is complied with	in line with CISPR 11/EN 55011 group 1 class A (for a shielded test setup); the instrument complies with the emission requirements stipulated by EN 55011, EN 61326-1 and EN 61326-2-1 class A, making the instrument suitable for use in industrial environments
Immunity		in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environment ²

Certifications	VDE-GS, cCSA _{US}
Calibration interval	1 year

 $^{^2}$ Test criterion is displayed noise level within ±1.5 div for input sensitivity of 5 mV/div.

Power supply	
AC supply	100 V to 240 V at
	50 Hz to 60 Hz and 400 Hz,
	max. 3.3 A to 1.5 A,
	in line with MIL-PRF-28800F section 3.5
Power consumption	max. 300 W
Safety	in line with IEC 61010-1, EN 61010-1,
	CAN/CSA-C22.2 No. 61010-1-04,
	UL 61010-1

Mechanical data		
Dimensions	$W \times H \times D$	427 mm × 249 mm × 204 mm
		(16.81 in × 9.80 in × 8.03 in)
Weight	without options, nominal	8.6 kg (18.96 lb)

Warranty	base unit	3 years
	accessories	1 year

Options

R&S®RTE-B1

Mixed signal option, additional 16 logic channels

Vertical system

Input channels		16 logic channels (D0 to D15)
Arrangement of input channels		arranged in two logic probes with
		8 channels each, assignment of the logic
		probes to the channels (D0 to D7 or D8 to
		D15) is displayed on the probe
Input impedance		100 kΩ ± 2 % ~4 pF (meas.) at probe
		tips
Maximum input frequency	signal with minimum input voltage swing	400 MHz (meas.)
	and hysteresis setting: normal	
Maximum input voltage		±40 V (V _p)
Minimum input voltage swing		500 mV (V _{pp}) (meas.)
Threshold groups		D0 to D3, D4 to D7, D8 to D11 and D12 to
		D15
Threshold level	range	±8 V in 25 mV steps
	predefined	CMOS 5.0 V, CMOS 3.3 V, CMOS 2.5 V,
		TTL, ECL, PECL, LVPECL
Threshold accuracy		±(100 mV + 3 % of threshold setting)
Comparator hysteresis		normal, robust, maximum

Horizontal system

Channel deskew	range for each channel	±200 ns
Channel-to-channel skew		< 500 ps (meas.)

Acquisition system

Sampling rate	max.	5 Gsample/s on each channel
Realtime waveform acquisition rate	max.	> 200 000 waveforms/s
Memory depth		100 Msample for every channel
Decimation		pulses lost due to decimation are
		displayed

Trigger system

Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Trigger modes			
Edge	triggers on specified slope (pos	triggers on specified slope (positive, negative or either) in the source signal	
	sources	any channel from D0 to D15 or any logical	
		combination of D0 to D15	
Width	triggers on positive or negative	pulse of specified width in the source signal; width can	
	be shorter, longer, equal, inside	e or outside the interval	
	sources	any channel from D0 to D15 or any logical	
		combination of D0 to D15	
	pulse width	200 ps to 10 s	
Timeout	triggers when the source signal	triggers when the source signal stays high, low or unchanged for a specified period of	
	time		
	sources	any channel from D0 to D15 or any logical	
		combination of D0 to D15	
	timeout	200 ps to 10 s	
Data2clock	triggers on setup time and hold	time violations between a clock signal and a data	
	signal; monitored time interval	signal; monitored time interval with a max. width of 200 ns and a position of	
	max. ±1 µs relative to the clock	max. ±1 μs relative to the clock edge	
	data signal	any subset of channels from D0 to D15 or	
		any user-defined bus signal	
	clock signal	any channel from D0 to D15	

Pattern	55	triggers when the source goes true or stays true for a period of time shorter, longer, equal, inside or outside a specified range	
	sources	any logical combination of D0 to D15 or any user-defined bus signal	
	pulse width	200 ps to 10 s	
State		triggers on the slope (positive, negative or either) of the clock signal when data signal matches a user-defined logical state	
	data signal	any logical combination of D0 to D15 or any user-defined bus signal	
	clock signal	any channel from D0 to D15	
Serial pattern		triggers on a serial data pattern of up to 32 bit; pattern bits may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative or either	
	data signal	any channel from D0 to D15 or any logical combination of D0 to D15	
	clock signal	any channel from D0 to D15 or any analog channel	
	max. data rate	1.00 Gbps	
	optional	I ² C, SPI, UART/RS-232, LIN, CAN, FlexRay™ and I ² S with dedicated software options	
	sources	any channel from D0 to D15	

Waveform measurements

General features	measurement panels, gate, statistics, long-term analysis and limit check; see features of the base unit
Measurement sources	all channels from D0 to D15 or any logical combination of D0 to D15
Automatic measurements	positive pulse width, negative pulse width, period, frequency, burst width, delay, phase, positive duty cycle, negative duty cycle, positive pulse count, negative pulse count, rising edge count, falling edge count
Additional cursor function	display of decoded bus value at the cursor position

Waveform math

Function	any logical combination of D0 to D15

Search and mark functions

The search function will be available in a future software release.

Display characteristics

Display of logical channels		selectable size and position on screen, diagram configuration by dragging and dropping signal icons
Bus decode	number of bus signals	4
	bus types	unclocked and clocked
	display types	decoded bus, logical signal, bus + logical signal, amplitude signal, amplitude + logical signal, tabulated list (decoded time interval selected with cursors)
	position and size	size and position on screen selectable
	data format of decoded bus	hex, unsigned integer, signed integer, fractional, binary
	data format of amplitude signal	unsigned integer, signed integer, fractional, binary offset
Channel activity display		independent of the scope acquisition, the state (stays low, stays high or toggles) of the channels from D0 to D15 is displayed in the signal icon

R&S®RTE-B10

Additional GPIB interface	
Function	interface in line with IEC 625-2 (IEEE 488.2)
Command set	SCPI 1999.0
Connector	24-pin Amphenol female
Interface functions	SH1, AH1, T6, L4, SR1, RL1, PP1, DC1, DT1, C0

R&S®RTE-B18

Additional removable solid state disk		
Disk type solid state disk		
Disk size ≥ 240 Gbyte (nom.)		
Firmware	installed upon delivery	

R&S®RTE-B19

Additional removable hard disk	
Disk type hard disk	
Disk size ≥ 500 Gbyte (nom.)	
Firmware	installed upon delivery

Protocol configuration	bit rate	up to 3.4 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for I ² C triggering and decoding
	device list	associate frame address with symbolic ID
Trigger	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, restart, missing ACK, address, data, address + data
	address setup	7 bit or 10 bit address (value in hex, decimal, octal or binary); ACK, NACK or either; read, write or either; R/W bit included in address value or apart; condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); condition =, \neq ; \geq , \leq , in range, out of range; offset within frame in range from 0 byte to 4095 byte
Decode	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, start/restart, address, R/W bit, data ACK/NACK, stop, error
	address and data format	hex, decimal, octal, binary, ASCII; symbolic names for user-defined subset of addresses
Search	search event setup	combination of start, stop, restart, missing ACK, address, data, address + data
	event settings	same as trigger event settings

SPI serial triggering and decod	ing	
Protocol configuration	type	2-wire, 3-wire and 4-wire SPI
	bit rate	up to 50 Mbps (auto-detected)
	bit order	LSB first, MSB first
	word size	4 bit to 32 bit
	frame condition	SS, timeout
	polarity (MOSI, MISO, SS, CLK)	active high, active low
	phase (CLK)	first edge, second edge
	auto threshold setup	assisted threshold configuration for SPI
		triggering and decoding
Trigger	source (MOSI, MISO, SS, CLK)	any input channel or logical channel
	trigger event setup	start of frame, MOSI, MISO, MOSI + MISO
	data setup	data pattern up to 256 bit (hex or binary);
		condition =, ≠; offset within frame in range
		from 0 bit to 32767 bit
Decode	source (MOSI, MISO, SS, CLK)	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	frame, word, error
	data format	hex, decimal, octal, binary, ASCII

Protocol configuration	bit rate	300 bps to 20 Mbps
	signal polarity	idle low, idle high
	number of bits	5 bit to 8 bit
	bit order	LSB first, MSB first
	parity	odd, even, mark, space, none
	stop bit	1, 1.5 or 2 bit periods
	end of packet	word, timeout, none
	auto threshold setup	assisted threshold configuration for
		UART triggering and decoding
Trigger	source (TX and RX)	any input channel or logical channel
	trigger event setup	start bit, packet start, data, parity error,
		break condition
	data setup	data pattern up to 256 bit (hex, decimal,
		octal, binary or ASCII); condition =, ≠;
		offset within packet in range 0 bit to
		32767 bit
Decode	source (TX and RX)	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	packet, data payload, start error, parity
		error, stop error
	data format	hex, decimal, octal, binary, ASCII

CAN serial triggering and deco		
Protocol configuration	signal type	CAN_H, CAN_L
	bit rate	100 bps to 1 Mbps
	sampling point	5 % to 95 % within bit period
	device list	associate frame identifier with symbolic ID
		load DBC file content
	auto threshold setup	assisted threshold configuration for CAN
		triggering and decoding
Trigger	source	any input channel or logical channel
	trigger event setup	start of frame, frame type, identifier,
		identifier + data, symbolic, error condition
		(any combination of CRC error, bit stuffing
		error, form error and ACK error)
	identifier setup	frame type (data, remote or both),
		identifier type (standard or extended);
		condition =, \neq , \geq , \leq , in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal,
		octal or binary); big-endian or little-endian;
		condition =, \neq ; \geq , \leq , in range, out of range
	symbolic setup	message name, signal name; numeric
		signal condition =, \neq , \geq , \leq , in range, out of
		range; enumerated signal condition =, ≠,
		≥, ≤
Decode	source	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	start of frame, identifier, DLC, data
		payload, CRC, end of frame, error frame,
		overload frame, CRC error, bit stuffing
		error
	data format	hex, decimal, octal, binary, ASCII,
		symbolic

Search	source	any input channel or logical channel
	search event setup	combination of start of frame, frame type, identifier, identifier + data, error condition (any combination of CRC error, bit stuffing error, form error and ACK error) or only symbolic
	event settings	same as trigger event settings

Protocol configuration	version	1.3, 2.x or SAE J602; mixed traffic is supported
	bit rate	standard bit rate (1.2/2.4/4.8/9.6/10.417/ 19.2 kbps) or user-defined bit rate in range from 1 kbps to 20 kbps
	device list	associate frame identifier with symbolic ID, data length and protocol version
	auto threshold setup	assisted threshold configuration for LIN triggering and decoding
Trigger	source	any input channel
gg.	trigger event setup	start of frame (sync break), identifier, identifier + data, wakeup frame, error condition (any combination of checksum error, parity error and sync field error)
	identifier setup	range from 0d to 63d; select condition =, ≠, ≥, ≤, in range, out of range for trigger "identifier"; select single identifier and condition = for trigger "identifier + data"
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); condition =, \neq , \geq , \leq , in range, out of range
Decode	source (TX and RX)	any input channel, math waveform, reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, frame identifier, data payload, checksum, error condition
	data format	hex, decimal, octal, binary, ASCII
Search	search event setup	combination of start of frame (sync break), identifier, identifier + data, wakeup frame, error condition (any combination of checksum error, parity error and sync field error)
	event settings	same as trigger event settings

FlexRay™ serial triggering and	decoding	
Protocol configuration	signal type	single-ended, differential, logic
	channel type	channel A, channel B
	bit rate	standard bit rates (2.5/5.0/10.0 Mbps)
	device list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration for
		FlexRay™ triggering and decoding
	source	any input channel or logical channel
Trigger	trigger event setup	start of frame, header + data, symbol,
		wakeup, error condition (any combination
		of FSS error, BSS error, FES error, header
		CRC error and frame CRC error)
	header setup	indicator bits, identifier, payload length,
		cycle count
	indicator bits setup	payload preamble bit, null frame bit, sync
		frame bit and startup frame bit separately
		configurable (1, 0 or don't care)
	identifier setup	condition =, \neq , \geq , \leq , in range, out of range
	payload length setup	condition =, \neq , \geq , \leq , in range, out of range
	cycle count	condition =, \neq , \geq , in range, out of range;
		step parameter for selection of non-
		contiguous values within provided range
	data setup	data pattern up to 8 byte (hex, decimal,
		octal or binary); condition =, \neq , \geq , in
		range, out of range; offset within frame in
		range from 0 byte to 253 byte
Decode	source	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	frame, frame header, identifier, payload
		length, header CRC, cycle count, data
		payload, frame CRC, error condition
	data format	hex, decimal, octal, binary, ASCII
Search	search event setup	combination of start of frame, header +
		data, symbol, wakeup, error condition (any
		combination of FSS error, BSS error, FES
		error, header CRC error and frame CRC
		error)
	event settings	same as trigger event settings

Protocol configuration	signal type	I ² S standard, left justified, right justified, TDM
	auto threshold setup	assisted threshold configuration for I2S triggering and decoding
Trigger	source	any input channel or logical channel
	trigger event setup	data, window, frame condition, word select, error condition
	data setup	data pattern of an audio channel up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition =, ≠; ≥, ≤, <, >, in range, out of range
	window setup	word count of data pattern of an audio channel up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition $=$, \neq ; \geq , \leq , $<$, $>$, in range, out of range
	frame condition setup	combination of audio channels in a frame, up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition =, \neq ; \geq , \leq , $<$, $>$, in range, out of range
	word select setup	rising or falling edge of word select input channel
	error condition setup	source of word select
Decode	source	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus and logical signal, tabulated list
	color coding	audio frame, frame error, incomplete frame
	data format	hex, unsigned decimal, signed decimal (two's complement), octal, binary, ASCII
Protocol measurements	audio display	display of audio waveform for specified audio channels
	long-term display	history of selected audio data as trace against measurements, waveforms and time index

MIL-STD-1553 serial triggering Protocol configuration	signal type	single-ended
Protocol configuration	bit rate	standard bit rate (1 Mbit/s)
	polarity	normal, inverted
	device list	associate frame identifier with symbolic IE
	auto threshold setup	assisted threshold configuration
	timing	min. gap (2 µs to 262 µs) or off; max. response (2 µs to 262 µs) or off
Trigger	trigger event setup	sync, word, data word, command/status word, command word, status word, error condition
	sync and word setup	all words, command/status word, data word
	data word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); data pattern (condition =, \neq , \geq , \leq , i range, out of range); payload data index (=, $<$, $>$, \geq , \leq , range); max length of data pattern is 4 byte
	command/status word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); 11 bit pattern (condition =, \neq , \geq , \leq , in range, out of range)
	command word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); subaddress/mode (condition =, \neq , \geq , \leq , in range, out of range); data word count/mode count (condition =, \neq , \geq , \leq , in range, out of range); direction (T/R)
	status word	RTA (condition =, ≠, ≥, ≤, in range, out of range); status flags (message error, instrumentation, service request, broadcast command, busy, subsystem flag, dynamic bus control, terminal flag)
	error condition	any combination of sync error, Mancheste error, parity error, timing error (see protocol configuration)
Decode	source	any analog input channel, math waveform reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame (word), sync, RTA, status bit field, parity, data field, error condition
	data format	hex, octal, binary, ASCII, signed, unsigne
Search	search event setup	sync, word, data word, command/status word, command word, status word, error condition
	event settings	same as trigger event settings

ARINC 429 triggering and deco	oding	
Protocol configuration	signal type	single-ended
-	bit rate	high (100 kbit/s)
		low (12 kbit/s to 14.5 kbit/s)
	polarity	A leg, B leg
	device list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration
	timing	min. gap (0 bit to 100 bit) or off; max. gap (0 bit to 1000 bit) or off
Trigger	trigger event setup	word start, word stop, label + data, error condition
	label + data setup	label (condition =, \neq , \geq , \leq , in range, out of range); data (condition =, \neq , \geq , \leq , in range, out of range); SDI/SSM
	error condition	any combination of coding error, parity error, timing error (see protocol configuration)
Decode	source	any analog input channel, math waveform, reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame (word), label, SDI, data, SSM, parity, error condition
	data format	hex, octal, binary, ASCII, signed, unsigned
Search	search event setup	word start, word stop, label + data, error condition
	event settings	same as trigger event settings

Ethernet serial decoding		
Protocol configuration	signal type	one channel, differential
	bit rate	selectable/adjustable
	auto threshold setup	assisted threshold configuration
	source (SDATA)	analog and math channels
	variants	10BASE-T, 100BASE-TX
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, details
	color coding	preamble, frame, destination address, source address, data
	data format	hex
Search	search event setup	frame, error
	frame	48 bit destination address, 48 bit source address, 16 bit length/type, 32 bit frame
		check; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	error	preamble, length error

CAN-FD serial triggering and de	ecoding	
Protocol configuration	signal type	CAN_H, CAN_L
	bit rate	
	arbitration rate	10 kbps to 1 Mbps
	data rate	10 kbps to 15 Mbps
	sampling point	5 % to 95 % within bit period
	device list	associate frame identifier with symbolic ID, load DBC file content
	auto threshold setup	assisted threshold configuration
Trigger	source	any input channel or logical channel
	trigger event setup	start of frame, frame type, identifier, identifier + data, symbolic, error condition (any combination of CRC error, bit stuffing error, form error and ACK error)
	identifier setup	frame type (data, remote or both), identifier type (standard or extended); condition =, ≠, ≥, ≤, in range, out of range
	FD bits	FDF and ESI (0, 1, X), BRS (0,1)
	data setup	data pattern up to 8 bytes in the complete data range (hex, decimal, octal or binary); condition =, \neq ; \geq , \leq , in range, out of range
	symbolic setup	message name, signal name; numeric signal condition =, \neq , \geq , \leq , in range, out of range; enumerated signal condition =, \neq , \geq , \leq
Decode	source	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	start of frame, identifier, FD bits, DLC, data payload, CRC, end of frame, error frame, overload frame, CRC error, bit stuffing error
	data format	hex, decimal, octal, binary, ASCII, symbolic
Search	source	any input channel or logical channel
	search event setup	combination of start of frame, frame type, identifier, identifier + data, error condition (any combination of CRC error, bit stuffing error, form error and ACK error) or only symbolic
	event settings	same as trigger event settings

SENT serial triggering and deco	oding	
Protocol configuration	signal type	data signal
	clock period (clock tick)	1 μs to 100 μs
	clock tolerance	0 % to 25 %
	data nibbles	1 to 6
	serial message type	none, Short Serial Message and
		Enhanced Serial Message
	CRC version	Legacy (Feb 2008) and v2010 (latest)
	CRC calculation	SAE J2716 standard and TLE 4998X
	pause pulse	no, yes, for constant frame length
	frame length in clock ticks (applicable only	104 to 922
	when pause pulse = constant frame	
	length)	

Trigger	source	any analog input channel
	trigger event setup	calibration or sync, transmission
		sequence, serial message and
		error condition
	transmission sequence status nibble setup	from 0 to F, condition =, \neq , \geq , \leq , in range, out of range
	transmission sequence data nibbles setup	each nibble value from 0 to F, condition =, \neq , \geq , \leq , in range, out of range
	serial message identifier setup	from 00 to FF, condition =, \neq , \geq , \leq , in range, out of range
	serial message identifier type setup (applicable only when the serial protocol = Enhanced Serial Message in protocol configuration)	4 bit and 8 bit
	serial message data setup	00 to FF (Short Serial Message), 000 to FFF (Enhanced Serial Message with 8 bit ID), 0000 to FFFF (Enhanced Serial Message with 4 bit ID)
	error condition setup	form error, calibration pulse error, pulse period error, CRC error and irregular frame length error
Decode	source	any analog input channel,
	display type	decoded bus, tabulated list
	color coding	transmission sequence: sync/calibration, status, data bits, CRC, pause pulse (optional), calibration pulse error, pulse period error, irregular frame length error and CRC error. serial message: identifier, data, CRC, form error, CRC error
	data format	hex, decimal, octal, binary, ASCII
Search	source	any analog input channel
	search event setup	calibration or sync, transmission sequence, serial message and error condition
	event settings	same as trigger event settings

High definition mode		
General description	The R&S®RTE-K17 high definition mode increases the numeric resolution of the waveform signal by using digital filtering, leading to a reduced noise. Because of the R&S®RTE digital trigger concept the signals with increased numeric resolution are use as input for triggering.	
Numeric resolution	bandwidth 10 kHz to 30 MHz	bit resolution 16 bit
	50 MHz 100 MHz	14 bit 13 bit
	200 MHz	12 bit
	300 MHz 500 MHz	11 bit 10 bit
Realtime sampling rate		max. 2.5 Gsample/s on each channel

Power analysis		
General description	The R&S®RTE-K31 power analysis option extends the R&S®RTE firmware measurement functionality focused on switched mode power supplies (SM DC/DC converters.	
Input	quality	evaluation of power quality at an AC input; measures real power, apparent power, reactive power, power factor and phase angle of power, frequency, crest factor, RMS of voltage and current
	harmonics	measures up to the 40th harmonic of the incoming line frequency; precompliance checking for IEC 61000-3-2 (A, B, C, D), RTCA DO-160, MIL-STD-1399, max. limit checks
	inrush current	measures peak inrush current; multiple measurement zones configurable with analysis of the post-inrush behavior
Switching/control loop	slew rate	The slope of current or voltage is measured at start and end of the switching cycle.
	modulation	measures modulation of switching frequency and duty cycle under steady state and start-up conditions
	dynamic on-resistance	measures resistance of the switching transistor(s) in active state
Power path	efficiency (only for 4 channel devices)	measures input and output power to calculate the efficiency of an SMPS
	safe operating area (SOA)	measures switching loss and conduction loss of a power device checks violation of voltage and current limits in which a power device can operate without damage; current versus voltage view (linear or log); violation mask is user-defined and editable in
	turn on/off	linear and log-log views measures relationship between AC and DC current, when turning the SMPS off and on
Output	ripple	measures AC components of output voltage and current, AC RMS, frequency, duty cycles, min./max./peak-to-peak amplitude
	spectrum	FFT analysis of output, measurement of frequency peaks
	transient response	This measurement captures the device behavior between the event of load changes and stabilization. includes peak (voltage, time), settling time, rise time, overshoot and delay
Deskew	automated	By using the R&S®RT-ZF20 probe deskew and calibration test fixture and Rohde & Schwarz voltage and current probes, the skew between the voltage and current signal is compensated automatically.
Reporting	easy reporting: Click to save a measurement. Report generation using user-selected test results from historical and currently-active tests. Put repeated and/or different measurements in one report.	

Protocol configuration	signal type	selectable,
	3 71	one channel, differential or single-ended,
		two channel, differential or single-ended
	bit rate	auto detected, selectable/adjustable
	auto threshold setup	assisted threshold configuration
	source (SDATA)	analog, math. channels
	bit encoding variants	Manchester,
		Manchester II,
		NRZ clocked,
		NRZ unclocked
	properties	active state, idle state, clock edge
Frame format	frame	multiple frame management,
		frame identification and sync,
		variable length frames,
		variable number of cells
	cells	name, size (bits), numeric format,
		bit order, color
	file storage of frame format	save/load as xml files
Trigger	variants	all
	trigger event setup	frame start, pattern
	frame start	gap, start bit
	pattern	up to 256 bit pattern within 65 535 bit
		frame ³
Decode	display type	decoded bus, logical signal, bus signal,
		tabulated list, result details
	color coding	according to cell configuration table
	data format	according to cell configuration table

MDIO serial triggering and deco		
Protocol configuration	bit rate	up to 5 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for
		MDIO triggering and decoding
	device list	associate frame address with symbolic ID
Trigger	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, ST, OP, PHY address, register address, data
	ST setup	01 (clause 22), 00 clause 45, any
	OP setup	address, write, post read, read, any
	PHY address setup	5 bit address (hex, decimal, octal or binary); equal
	PHY register (clause 22)/device type	5 bit value (hex, decimal, octal or binary);
	(clause 45) setup	equal
	data (clause 22)/data/address (clause 45)	16 bit value (hex, decimal, octal or binary); equal
Decode	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, PHY address, PHY register, address, data, turnaround
	PHYAD/PRTAD	symbolic names for user defined addresses
	address/data field format	hex, decimal, octal, binary, ASCII
Search	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	search event setup	start, stop, ST, OP, PHY address, register address, data
	event settings	same as trigger event settings

³ The pattern trigger will not be effective after Manchester violations.

USB 1.0/1.1/2.0/HSIC serial trigg	ering and decoding	
Protocol configuration	signal type	single-ended, differential
	protocol type	low, full, high speed and HSIC
	bit rate	standard bit rates (1.5/12/480 Mbit/s)
	source	any input channel
		any input channel
	probe type	simple and advanta
	for low and full speed	single-ended probe
	for high speed	differential probe (R&S®RT-ZDxx)
	for HSIC	single-ended probe(R&S®RT-ZSxx)
	auto threshold setup	assisted threshold configuration for
		USB triggering and decoding
Trigger	trigger event setup	start of packet, end of packet, PID token (IN, OUT, SETUP, SOF), PID data (Data0, Data1, Data2 ⁴ , MData ⁴), PID handshake (ACK, NAK, STALL, NYET ⁴), PID special (PRE ⁵ , ERR ⁴ , SPLIT ⁴ , PING ⁴); bus state (reset ⁵ , resume ⁵ , suspend ⁵); error condition
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT) ⁴	condition =, ≠, ≥, ≤, in range, out of range
	data setup	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)
	error condition	any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁵ and glitching error
Decode	source	any input channel, math waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	packet identifier, payload length, frame, address, endpoint, data payload, CRC5, CRC16, error condition
	data format	hexadecimal, decimal, octal, binary, ASCII, unsigned
Search	search event setup	combination of start of packet, PID token (IN, OUT, SETUP, SOF), PID data (Data0, Data1, Data2 ⁴ , MData ⁴), PID handshake (ACK, NAK, STALL, NYET ⁴), PID special (PRE ⁵ , ERR ⁴ , SPLIT ⁴ , PING ⁴); error condition (any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁵ and glitching error)
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT)	condition =, \neq , \geq , \leq , in range, out of range
	data setup	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)
	error condition	payload) any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁵ and glitching error

⁴ Only available in high speed and HSIC.

⁵ Only available in low and full speed.

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SpaceWire serial triggering and	d decoding	
Protocol configuration	signal type	two channels: strobe and data (differential or single-ended)
	bit rate	auto adjust (strobe + data)
	source	any analog input channels, logical channels ⁶ , math channels, reference channels
Trigger	trigger event setup	control frame, data pattern, null frame, time code, error condition
	control frame setup	any, FCT, EOP, EEP
	data pattern setup	8 bit (condition =, \neq , <, >, \geq , \leq , in range, out of range)
	time code setup	8 bit (condition =, \neq , <, >, \geq , \leq , in range, out of range)
	errors condition setup	parity, ESC
Decode	display type	decoded bus, logical signal, bus + logical signal, tabulated list, decode layers
	color coding	control frame, data frame, null frame, time code
	data format	hex
Search	search event setup	control frame, data pattern, null frame, time code, error
	event settings	same as trigger event settings

⁶ SpaceWire protocol trigger on logical channels is not available.

Ordering information

Designation	Туре	Order No.
Base unit (including standard accessories: R&S®RTE-ZP10 500 MHz passive probe p CD with manual, power cord)	er channel, accessories	s bag, quick start gu
Digital Oscilloscope		
200 MHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1022	1326.2000.22
200 MHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1024	1326.2000.24
350 MHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1032	1326.2000.32
350 MHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1034	1326.2000.34
500 MHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1052	1326.2000.52
500 MHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1054	1326.2000.54
1 GHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1102	1326.2000.62
1 GHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1104	1326.2000.64
1.5 GHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1152	1326.2000.72
1.5 GHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1154	1326.2000.74
2 GHz, 5 Gsample/s, 10/20 Msample, 2 channels	R&S®RTE1202	1326.2000.82
2 GHz, 5 Gsample/s, 10/40 Msample, 4 channels	R&S®RTE1204	1326.2000.84
Hardware options (plug-in)		
Mixed Signal Option, 400 MHz, 5 Gsample/s, 16 channels, 100 Msample/channel	R&S®RTE-B1	1317.4961.02
GPIB Interface	R&S®RTE-B10	1317.4978.02
Replacement SSD Hard Disk, incl. firmware	R&S®RTE-B18	1317.7002.02
Replacement Hard Disk, incl. firmware	R&S®RTE-B19	1317.7019.02
Memory Upgrade, 20 Msample per channel	R&S®RTE-B101	1326.1155.02
Memory Upgrade, 50 Msample per channel	R&S®RTE-B102	1326.1161.02
Bandwidth upgrade ⁷		
Upgrade of R&S®RTE1022/1024 to 350 MHz bandwidth	R&S®RTE-B200	1326.1384.02
Upgrade of R&S®RTE1022/1024 to 500 MHz bandwidth	R&S®RTE-B201	1326.1390.02
Upgrade of R&S®RTE1022/1024 to 1 GHz bandwidth	R&S®RTE-B202	1326.1403.02
Upgrade of R&S®RTE1022/1024 to 1.5 GHz bandwidth	R&S®RTE-B203	1326.1410.02
Upgrade of R&S®RTE1022/1024 to 2 GHz bandwidth	R&S®RTE-B204	1326.1426.02
Upgrade of R&S®RTE1032/1034 to 500 MHz bandwidth	R&S®RTE-B205	1326.1432.02
Upgrade of R&S®RTE1032/1034 to 1 GHz bandwidth	R&S®RTE-B206	1326.1449.02
Upgrade of R&S®RTE1032/1034 to 1.5 GHz bandwidth	R&S®RTE-B207	1326.1455.02
Upgrade of R&S®RTE1032/1034 to 2 GHz bandwidth	R&S®RTE-B208	1326.1461.02
Upgrade of R&S®RTE1052/1054 to 1 GHz bandwidth	R&S®RTE-B209	1326.1478.02
Upgrade of R&S®RTE1052/1054 to 1.5 GHz bandwidth	R&S®RTE-B210	1326.1484.02
Upgrade of R&S®RTE1052/1054 to 2 GHz bandwidth	R&S®RTE-B211	1326.1490.02
Upgrade of R&S®RTE1102/1104 to 1.5 GHz bandwidth	R&S®RTE-B212	1326.1503.02
Upgrade of R&S®RTE1102/1104 to 2 GHz bandwidth	R&S®RTE-B213	1326.1510.02
Upgrade of R&S®RTE1152/1154 to 2 GHz bandwidth	R&S®RTE-B214	1326.1526.02
Software options	TOO TITE-DETA	1020.1020.02
Serial triggering and decoding		
I ² C/SPI Serial Triggering and Decoding	R&S®RTE-K1	1326.1178.02
UART/RS-232/RS-422/RS-485 Serial Triggering and Decoding	R&S®RTE-K2	1326.1184.02
CAN/LIN Serial Triggering and Decoding	R&S®RTE-K3	1326.1190.02
FlexRay™ Serial Triggering and Decoding	R&S®RTE-K4	1326.1203.02
I'S Serial Triggering and Decoding	R&S®RTE-K5	1326.1210.02
MIL-STD-1553 Serial Triggering and Decoding	R&S®RTE-K6	1326.1226.02
ARINC 429 Triggering and Decoding	R&S®RTE-K7	1326.1232.02
Ethernet Serial Decoding	R&S®RTE-K8	1326.1332.02
CAN-FD Serial Triggering and Decoding	R&S®RTE-K9	1326.1332.02
SENT Serial Triggering and Decoding		
	R&S®RTE-K10	1326.1603.02
Manchester and NRZ Serial Triggering and Decoding	R&S®RTE-K50	1326.1326.02
MDIO Serial Triggering and Decoding	R&S®RTE-K55	1326.1255.02
USB 1.0/1.1/2.0/HSIC Serial Triggering and Decoding	R&S®RTE-K60	1326.1610.02
SpaceWire Serial Triggering and Decoding Analysis	R&S®RTE-K65	1326.2845.02
High Definition Mode, vertical resolution up to 16 bit	R&S®RTE-K17	1326.1261.02
Power Analysis	R&S®RTE-K31	1326.1278.02

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⁷ The bandwidth upgrade is performed at a Rohde & Schwarz service center, where the oscilloscope will also be calibrated.

Designation	Туре	Order No.
Probes		·
500 MHz, passive, 10:1, 1 MΩ 9.5 pF, max. 400 V	R&S®RT-ZP10	1409.7550.00
400 MHz, passive, high-voltage, 100:1, 50 MΩ 7.5 pF, 1 kV (RMS)	R&S®RT-ZH10	1409.7720.02
400 MHz, passive, high-voltage, 1000:1, 50 MΩ 7.5 pF, 1 kV (RMS)	R&S®RT-ZH11	1409.7737.02
1.0 GHz, active, 1 MΩ 0.8 pF	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS10	1410.4080.02
1.5 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS20	1410.3502.02
3.0 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS30	1410.4309.02
100 MHz, high-voltage, active, differential, 8 MΩ 3.5 pF, 1 kV (RMS) (CAT III)	R&S®RT-ZD01	1422.0703.02
1.0 GHz, active, differential, 1 MΩ 0.6 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD10	1410.4715.02
1.5 GHz, active, differential, 1 MΩ 0.6 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD20	1410.4409.02
3.0 GHz, active, differential, 1 MΩ 0.6 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD30	1410.4609.02
10 MHz, current, AC/DC, 0.01 V/A, 150 A (RMS)	R&S®RT-ZC10	1409.7750K02
100 MHz, current, AC/DC, 0.1 V/A, 30 A (RMS)	R&S®RT-ZC20	1409.7766K02
120 MHz, AC/DC, 1 V/A, 5 A (RMS)	R&S®RT-ZC30	1409.7772K02
2 MHz, current, AC/DC, 0.01 V/A, 500 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC05B	1409.8204.02
10 MHz, current, AC/DC, 0.01 V/A, 150 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC10B	1409.8210.02
50 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC15B	1409.8227.02
100 MHz, current, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC20B	1409.8233.02
Probe accessories		
Accessory Set for R&S®RTE-ZP10 passive probe (2.5 mm probe tip)	R&S®RT-ZA1	1409.7566.00
Spare Accessory Set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA2	1416.0405.02
Pin Set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA3	1416.0411.02
Mini Clips	R&S®RT-ZA4	1416.0428.02
Micro Clips	R&S®RT-ZA5	1416.0434.02
Lead Set	R&S®RT-ZA6	1416.0440.02
Pin Set for R&S®RT-ZD10/20/30	R&S®RT-ZA7	1417.0609.02
Pin Set for R&S®RT-ZD40	R&S®RT-ZA8	1417.0867.02
Adapter SMA(f) to BNC(m)	R&S®RT-ZA10	1416.0457.02
Probe Power Supply	R&S®RT-ZA13	1409.7789.02
External Attenuator, incl. adjustment tool	R&S®RT-ZA15	1410.4744.02
Accessories		
Front Cover, for R&S®RTO/RTE digital oscilloscopes	R&S®RTO-Z1	1317.6970.02
Soft Case, for R&S®RTO/RTE digital oscilloscopes and accessories	R&S®RTO-Z3	1304.9118.02
Transit Case, for R&S®RTO/RTE digital oscilloscopes and accessories	R&S®RTO-Z4	1317.7025.02
Probe Pouch, for R&S®RTO/RTE digital oscilloscopes	R&S®RTO-Z5	1317.7031.02
Probe Deskew and Calibration Test Fixture	R&S®RT-ZF20	1800.0004.02
Probe Set for E and H Near-Field Measurements, 9 kHz to 1 GHz	R&S®HZ-14	1026.7744.03
Compact Probe Set for E and H Near-Field Measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02
3 GHz, 20 dB Preamplifier, 100 V to 230 V Power Adapter, for R&S®HZ-15	R&S®HZ-16	1147.2720.02
19" Rackmount Kit, for R&S®RTO/RTE digital oscilloscopes with 6 HU	R&S®ZZA-RTO	1304.8286.02

Version 06.00, February 2016

Service options		
Extended Warranty, one year	R&S®WE1	Please contact your local
Extended Warranty, two years	R&S®WE2	Rohde & Schwarz sales office.
Extended Warranty with Calibration Coverage, one year	R&S®CW1	
Extended Warranty with Calibration Coverage, two years	R&S®CW2	

Extended warranty with a term of one and two years (WE1 and WE2)

Repairs carried out during the contract term are free of charge ⁸. Necessary calibration and adjustments carried out during repairs are also covered.

Extended warranty with calibration (CW1 and CW2)

Enhance your extended warranty by adding calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated, inspected and maintained during the term of the contract. It includes all repairs ⁸ and calibration at the recommended intervals as well as any calibration carried out during repairs or option upgrades.

⁸ Excluding defects caused by incorrect operation or handling and force majeure. Wear-and-tear parts are not included.

Service that adds value

- Uncompromising qualityLong-term dependability

About Rohde & Schwarz

The Rohde & Schwarz electronics group offers innovative solutions in the following business fields: test and measurement, broadcast and media, secure communications, cybersecurity, radiomonitoring and radiolocation. Founded more than 80 years ago, this independent company has an extensive sales and service network and is present in more than 70 countries. The electronics group is among the world market leaders in its established business fields. The company is headquartered in Munich, Germany. It also has regional headquarters in Singapore and Columbia, Maryland, USA, to manage its operations in these regions.

Sustainable product design

- Environmental compatibility and eco-footprint
- Energy efficiency and low emissions
- Longevity and optimized total cost of ownership

Certified Quality Management ISO 9001

Certified Environmental Management ISO 14001

Rohde & Schwarz GmbH & Co. KG

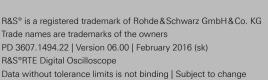
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